

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Michael P. Chrisp Docket No. : IL-11127
Serial No. : Art Unit :
Filed : Examiner :
For : COMPACT REFLECTIVE IMAGING SPECTROMETER
UTILIZING IMMERSSED GRATINGS

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
Alexandria, VA 22313-1450

Dear Sir:

Forwarded herewith is an Information Disclosure Statement, Form 1449, in the above-identified application. Copies of the cited references are enclosed: 14 U.S. Patent Documents and 1 Foreign Patent Document.

The above-mentioned disclosures, which are not admitted as prior art, are identified on the enclosed Form 1449.

Respectfully submitted,

Dated: September 8, 2003

Eddie E. Scott
Eddie E. Scott
Attorney for Applicant
Registration No. 25,220

Enclosures: As noted above

Please type a plus sign (+) inside this box +

PTO/SB/08A (08-00)

Approved for use through 10/31/2002. OMB 0651-0031

U.S. Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE
Under the Paperwork Reduction Act of 1995, persons are required to respond to a collection of information unless it contains a valid OMB control number.

<p>Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)</p>				Complete if Known	
				Application Number	
				Filing Date	
				First Named Inventor	Michael P. Chrisp
				Group Art Unit	
				Examiner Name	
Sheet 1 of 1	Attorney Docket Number IL-11127				

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	U.S. Patent Document Number	Kind Code ² (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		5,127,728		Warren, et al.	07-07-1992	
		5,717,487		Davies	01-10-1998	
		5,781,290		Bittner, et al.	07-14-1998	
		5,880,834		Chrisp	03-09-1999	
		6,016,220		Cook	01-18-2000	
		6,078,048		Stevens, et al.	06-20-2000	
		6,100,974		Reininger	08-08-2000	
		6,122,051		Ansley, et al.	09-19-2000	
		6,266,140	B1	Xiang, et al.	07-24-2001	
		6,388,799	B1	Arnone, et al.	05-14-2002	
		6,538,737	B2	Sandstrom, et al.	03-25-2003	
		2003/0016355	A1	Koike, et al.	01-23-2003	
		2002/0101587	A1	Wilson, et al.	08-01-2002	
		2002/0135770	A1	Lewis, et al.	09-26-2002	

FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Foreign Patent Document Office ³	Number ⁴	Kind Code ⁵ (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
			WO 99/63311		Ansley, et al.	12-09-1999		

Examiner Signature	Date Considered
--------------------	-----------------

Examiner: initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Unique citation designation number. ² See attached Kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

SEND TO: Commissioner for Patents, Washington, DC 20231.